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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	8375
Number of Logic Elements/Cells	67000
Total RAM Bits	4526080
Number of I/O	295
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-70ea-6fn484c

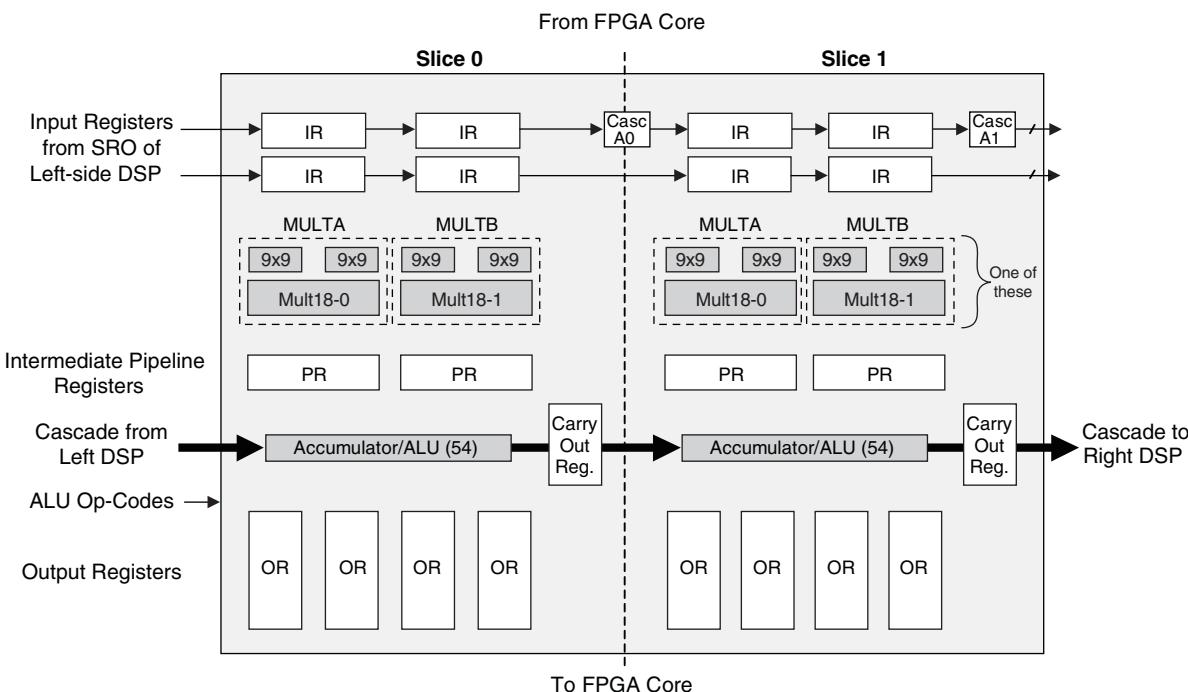
as, overflow, underflow and convergent rounding, etc.

- Flexible cascading across slices to get larger functions

- RTL Synthesis friendly synchronous reset on all registers, while still supporting asynchronous reset for legacy users
- Dynamic MUX selection to allow Time Division Multiplexing (TDM) of resources for applications that require processor-like flexibility that enables different functions for each clock cycle

For most cases, as shown in Figure 2-24, the LatticeECP3 DSP slice is backwards-compatible with the LatticeECP2™ sysDSP block, such that, legacy applications can be targeted to the LatticeECP3 sysDSP slice. The functionality of one LatticeECP2 sysDSP Block can be mapped into two adjacent LatticeECP3 sysDSP slices, as shown in Figure 2-25.

Figure 2-24. Simplified sysDSP Slice Block Diagram



MAC DSP Element

In this case, the two operands, AA and AB, are multiplied and the result is added with the previous accumulated value. This accumulated value is available at the output. The user can enable the input and pipeline registers, but the output register is always enabled. The output register is used to store the accumulated value. The ALU is configured as the accumulator in the sysDSP slice in the LatticeECP3 family can be initialized dynamically. A registered overflow signal is also available. The overflow conditions are provided later in this document. Figure 2-27 shows the MAC sysDSP element.

Figure 2-27. MAC DSP Element

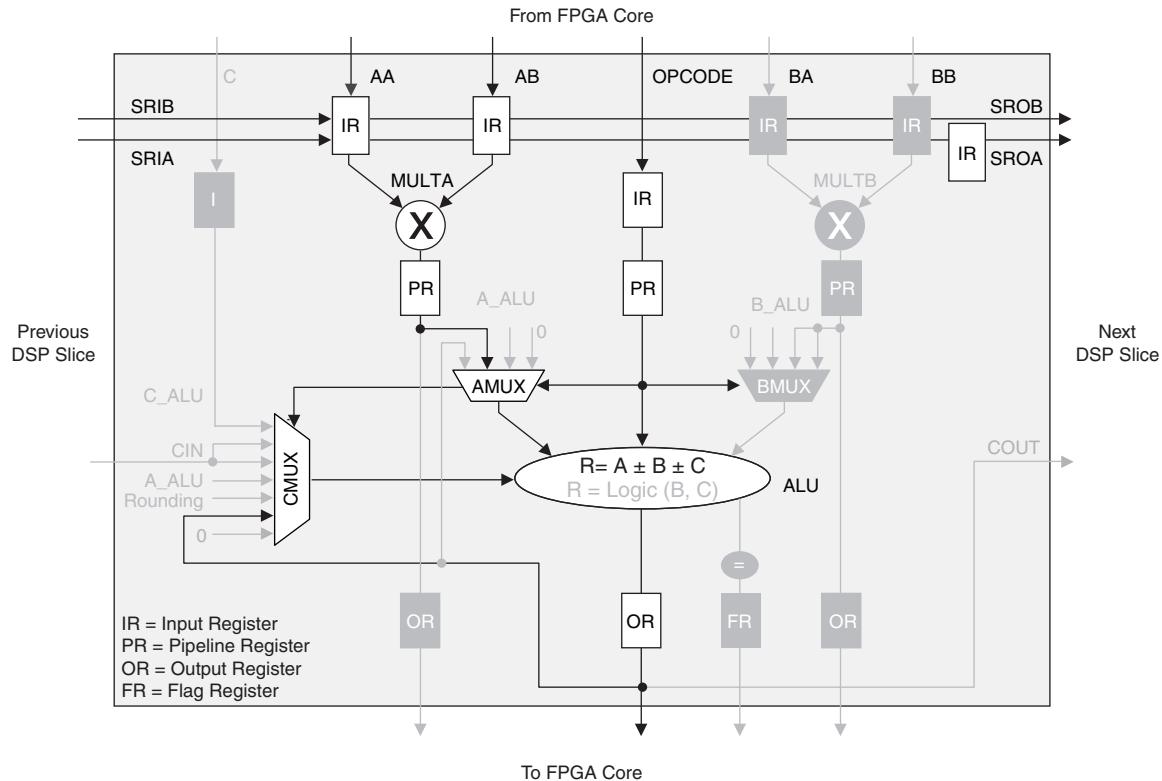


Table 2-16. Selectable Master Clock (MCCLK) Frequencies During Configuration (Nominal)

MCCLK (MHz)	MCCLK (MHz)
	10
2.5 ¹	13
4.3	15 ²
5.4	20
6.9	26
8.1	33 ³
9.2	

1. Software default MCCLK frequency. Hardware default is 3.1 MHz.

2. Maximum MCCLK with encryption enabled.

3. Maximum MCCLK without encryption.

Density Shifting

The LatticeECP3 family is designed to ensure that different density devices in the same family and in the same package have the same pinout. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likelihood of success in each case. An example is that some user I/Os may become No Connects in smaller devices in the same package. Refer to the [LatticeECP3 Pin Migration Tables](#) and Diamond software for specific restrictions and limitations.

DC Electrical Characteristics

Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$I_{IL}, I_{IH}^{1,4}$	Input or I/O Low Leakage	$0 \leq V_{IN} \leq (V_{CCIO} - 0.2 \text{ V})$	—	—	10	μA
$I_{IH}^{1,3}$	Input or I/O High Leakage	$(V_{CCIO} - 0.2 \text{ V}) < V_{IN} \leq 3.6 \text{ V}$	—	—	150	μA
I_{PU}	I/O Active Pull-up Current	$0 \leq V_{IN} \leq 0.7 V_{CCIO}$	-30	—	-210	μA
I_{PD}	I/O Active Pull-down Current	$V_{IL} (\text{MAX}) \leq V_{IN} \leq V_{CCIO}$	30	—	210	μA
I_{BHLS}	Bus Hold Low Sustaining Current	$V_{IN} = V_{IL} (\text{MAX})$	30	—	—	μA
I_{BHHS}	Bus Hold High Sustaining Current	$V_{IN} = 0.7 V_{CCIO}$	-30	—	—	μA
I_{BHLO}	Bus Hold Low Overdrive Current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	210	μA
I_{BHHO}	Bus Hold High Overdrive Current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	-210	μA
V_{BHT}	Bus Hold Trip Points	$0 \leq V_{IN} \leq V_{IH} (\text{MAX})$	$V_{IL} (\text{MAX})$	—	$V_{IH} (\text{MIN})$	V
C1	I/O Capacitance ²	$V_{CCIO} = 3.3 \text{ V}, 2.5 \text{ V}, 1.8 \text{ V}, 1.5 \text{ V}, 1.2 \text{ V},$ $V_{CC} = 1.2 \text{ V}, V_{IO} = 0 \text{ to } V_{IH} (\text{MAX})$	—	5	8	pf
C2	Dedicated Input Capacitance ²	$V_{CCIO} = 3.3 \text{ V}, 2.5 \text{ V}, 1.8 \text{ V}, 1.5 \text{ V}, 1.2 \text{ V},$ $V_{CC} = 1.2 \text{ V}, V_{IO} = 0 \text{ to } V_{IH} (\text{MAX})$	—	5	7	pf

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.
2. $T_A = 25^\circ\text{C}$, $f = 1.0 \text{ MHz}$.
3. Applicable to general purpose I/Os in top and bottom banks.
4. When used as V_{REF} , maximum leakage = 25 μA .

LVDS25E

The top and bottom sides of LatticeECP3 devices support LVDS outputs via emulated complementary LVCMS outputs in conjunction with a parallel resistor across the driver outputs. The scheme shown in Figure 3-1 is one possible solution for point-to-point signals.

Figure 3-1. LVDS25E Output Termination Example

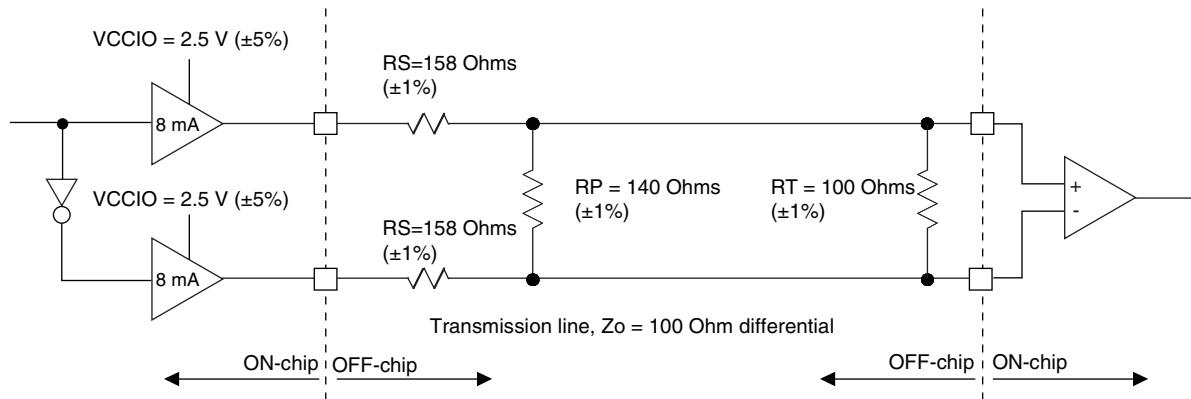


Table 3-1. LVDS25E DC Conditions

Parameter	Description	Typical	Units
V_{CCIO}	Output Driver Supply (+/-5%)	2.50	V
Z_{OUT}	Driver Impedance	20	Ω
R_S	Driver Series Resistor (+/-1%)	158	Ω
R_P	Driver Parallel Resistor (+/-1%)	140	Ω
R_T	Receiver Termination (+/-1%)	100	Ω
V_{OH}	Output High Voltage	1.43	V
V_{OL}	Output Low Voltage	1.07	V
V_{OD}	Output Differential Voltage	0.35	V
V_{CM}	Output Common Mode Voltage	1.25	V
Z_{BACK}	Back Impedance	100.5	Ω
I_{DC}	DC Output Current	6.03	mA

LVCMS33D

All I/O banks support emulated differential I/O using the LVCMS33D I/O type. This option, along with the external resistor network, provides the system designer the flexibility to place differential outputs on an I/O bank with 3.3 V V_{CCIO} . The default drive current for LVCMS33D output is 12 mA with the option to change the device strength to 4 mA, 8 mA, 16 mA or 20 mA. Follow the LVCMS33 specifications for the DC characteristics of the LVCMS33D.

LatticeECP3 External Switching Characteristics (Continued)^{1, 2, 3, 13}

Over Recommended Commercial Operating Conditions

Parameter	Description	Device	-8		-7		-6		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{H_DEL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-150EA	0.0	—	0.0	—	0.0	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	ECP3-150EA	—	500	—	420	—	375	MHz
t _{CO}	Clock to Output - PIO Output Register	ECP3-70EA/95EA	—	3.8	—	4.2	—	4.6	ns
t _{SU}	Clock to Data Setup - PIO Input Register	ECP3-70EA/95EA	0.0	—	0.0	—	0.0	—	ns
t _H	Clock to Data Hold - PIO Input Register	ECP3-70EA/95EA	1.4	—	1.6	—	1.8	—	ns
t _{SU_DEL}	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-70EA/95EA	1.3	—	1.5	—	1.7	—	ns
t _{H_DEL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-70EA/95EA	0.0	—	0.0	—	0.0	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	ECP3-70EA/95EA	—	500	—	420	—	375	MHz
t _{CO}	Clock to Output - PIO Output Register	ECP3-35EA	—	3.7	—	4.1	—	4.5	ns
t _{SU}	Clock to Data Setup - PIO Input Register	ECP3-35EA	0.0	—	0.0	—	0.0	—	ns
t _H	Clock to Data Hold - PIO Input Register	ECP3-35EA	1.2	—	1.4	—	1.6	—	ns
t _{SU_DEL}	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-35EA	1.3	—	1.4	—	1.5	—	ns
t _{H_DEL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-35EA	0.0	—	0.0	—	0.0	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	ECP3-35EA	—	500	—	420	—	375	MHz
t _{CO}	Clock to Output - PIO Output Register	ECP3-17EA	—	3.5	—	3.9	—	4.3	ns
t _{SU}	Clock to Data Setup - PIO Input Register	ECP3-17EA	0.0	—	0.0	—	0.0	—	ns
t _H	Clock to Data Hold - PIO Input Register	ECP3-17EA	1.3	—	1.5	—	1.6	—	ns
t _{SU_DEL}	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-17EA	1.3	—	1.4	—	1.5	—	ns
t _{H_DEL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-17EA	0.0	—	0.0	—	0.0	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	ECP3-17EA	—	500	—	420	—	375	MHz

General I/O Pin Parameters Using Dedicated Clock Input Primary Clock with PLL with Clock Injection Removal Setting²

t _{COPLL}	Clock to Output - PIO Output Register	ECP3-150EA	—	3.3	—	3.6	—	39	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	ECP3-150EA	0.7	—	0.8	—	0.9	—	ns
t _{HPLL}	Clock to Data Hold - PIO Input Register	ECP3-150EA	0.8	—	0.9	—	1.0	—	ns
t _{SU_DELPLL}	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-150EA	1.6	—	1.8	—	2.0	—	ns
t _{H_DELPLL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-150EA	—	0.0	—	0.0	—	0.0	ns
t _{COPLL}	Clock to Output - PIO Output Register	ECP3-70EA/95EA	—	3.3	—	3.5	—	3.8	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	ECP3-70EA/95EA	0.7	—	0.8	—	0.9	—	ns

LatticeECP3 External Switching Characteristics (Continued)^{1, 2, 3, 13}

Over Recommended Commercial Operating Conditions

Parameter	Description	Device	-8		-7		-6		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{HPLL}	Clock to Data Hold - PIO Input Register	ECP3-70EA/95EA	0.7	—	0.7	—	0.8	—	ns
t _{SU_DELPLL}	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-70EA/95EA	1.6	—	1.8	—	2.0	—	ns
t _{H_DELPLL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-70EA/95EA	0.0	—	0.0	—	0.0	—	ns
t _{COPLL}	Clock to Output - PIO Output Register	ECP3-35EA	—	3.2	—	3.4	—	3.6	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	ECP3-35EA	0.6	—	0.7	—	0.8	—	ns
t _{HPLL}	Clock to Data Hold - PIO Input Register	ECP3-35EA	0.3	—	0.3	—	0.4	—	ns
t _{SU_DELPLL}	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-35EA	1.6	—	1.7	—	1.8	—	ns
t _{H_DELPLL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-35EA	0.0	—	0.0	—	0.0	—	ns
t _{COPLL}	Clock to Output - PIO Output Register	ECP3-17EA	—	3.0	—	3.3	—	3.5	ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	ECP3-17EA	0.6	—	0.7	—	0.8	—	ns
t _{HPLL}	Clock to Data Hold - PIO Input Register	ECP3-17EA	0.3	—	0.3	—	0.4	—	ns
t _{SU_DELPLL}	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-17EA	1.6	—	1.7	—	1.8	—	ns
t _{H_DELPLL}	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-17EA	0.0	—	0.0	—	0.0	—	ns
Generic DDR¹²									
Generic DDRX1 Inputs with Clock and Data (>10 Bits Wide) Centered at Pin (GDDRX1_RX.SCLK.Centered) Using PCLK Pin for Clock Input									
t _{SUGDDR}	Data Setup Before CLK	All ECP3EA Devices	480	—	480	—	480	—	ps
t _{HOGDDR}	Data Hold After CLK	All ECP3EA Devices	480	—	480	—	480	—	ps
f _{MAX_GDDR}	DDRX1 Clock Frequency	All ECP3EA Devices	—	250	—	250	—	250	MHz
Generic DDRX1 Inputs with Clock and Data (>10 Bits Wide) Aligned at Pin (GDDRX1_RX.SCLK.PLL.Aligned) Using PLLCLKIN Pin for Clock Input									
Data Left, Right, and Top Sides and Clock Left and Right Sides									
t _{DVACLKGDDR}	Data Setup Before CLK	All ECP3EA Devices	—	0.225	—	0.225	—	0.225	UI
t _{DVECLKGDDR}	Data Hold After CLK	All ECP3EA Devices	0.775	—	0.775	—	0.775	—	UI
f _{MAX_GDDR}	DDRX1 Clock Frequency	All ECP3EA Devices	—	250	—	250	—	250	MHz
Generic DDRX1 Inputs with Clock and Data (>10 Bits Wide) Aligned at Pin (GDDRX1_RX.SCLK.Aligned) Using DLL - CLKIN Pin for Clock Input									
Data Left, Right and Top Sides and Clock Left and Right Sides									
t _{DVACLKGDDR}	Data Setup Before CLK	All ECP3EA Devices	—	0.225	—	0.225	—	0.225	UI
t _{DVECLKGDDR}	Data Hold After CLK	All ECP3EA Devices	0.775	—	0.775	—	0.775	—	UI
f _{MAX_GDDR}	DDRX1 Clock Frequency	All ECP3EA Devices	—	250	—	250	—	250	MHz
Generic DDRX1 Inputs with Clock and Data (<10 Bits Wide) Centered at Pin (GDDRX1_RX.DQS.Centered) Using DQS Pin for Clock Input									
t _{SUGDDR}	Data Setup After CLK	All ECP3EA Devices	535	—	535	—	535	—	ps
t _{HOGDDR}	Data Hold After CLK	All ECP3EA Devices	535	—	535	—	535	—	ps
f _{MAX_GDDR}	DDRX1 Clock Frequency	All ECP3EA Devices	—	250	—	250	—	250	MHz
Generic DDRX1 Inputs with Clock and Data (<10bits wide) Aligned at Pin (GDDRX1_RX.DQS.Aligned) Using DQS Pin for Clock Input									
Data and Clock Left and Right Sides									
t _{DVACLKGDDR}	Data Setup Before CLK	All ECP3EA Devices	—	0.225	—	0.225	—	0.225	UI

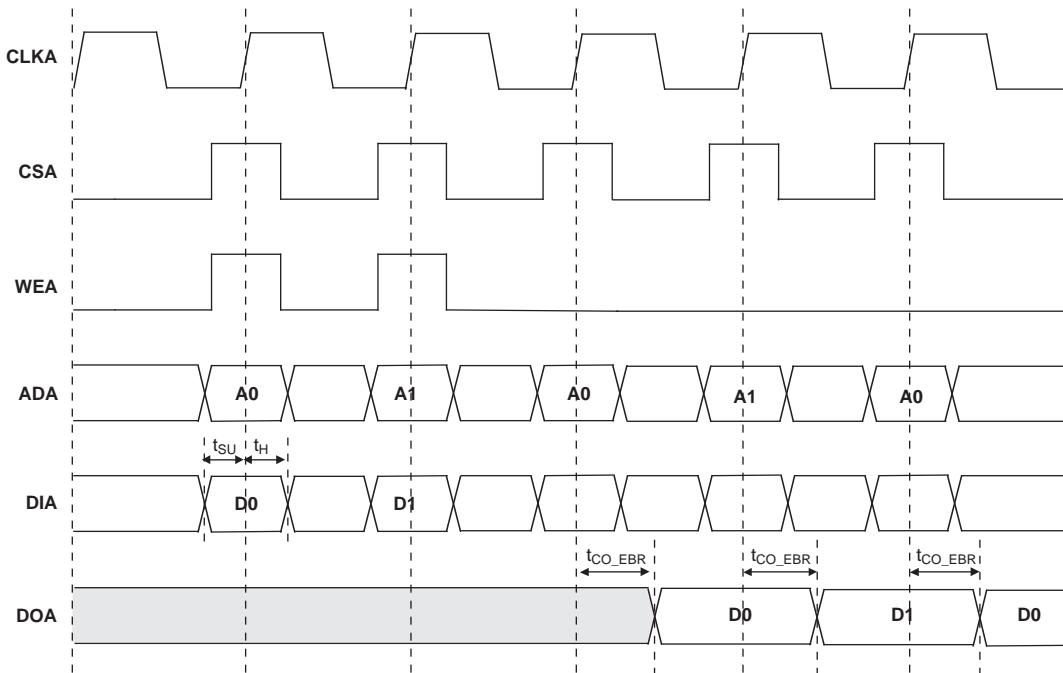
LatticeECP3 External Switching Characteristics (Continued)^{1, 2, 3, 13}

Over Recommended Commercial Operating Conditions

Parameter	Description	Device	-8		-7		-6		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
$t_{DVECLKGDDR}$	Data Hold After CLK	All ECP3EA Devices	0.775	—	0.775	—	0.775	—	UI
f_{MAX_GDDR}	DDRX1 Clock Frequency	All ECP3EA Devices	—	250	—	250	—	250	MHz
Generic DDRX2 Inputs with Clock and Data (>10 Bits Wide) Centered at Pin (GDDRX2_RX.ECLK.Centered) Using PCLK Pin for Clock Input									
Left and Right Sides									
t_{SUGDDR}	Data Setup Before CLK	ECP3-150EA	321	—	403	—	471	—	ps
t_{HOGDDR}	Data Hold After CLK	ECP3-150EA	321	—	403	—	471	—	ps
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-150EA	—	405	—	325	—	280	MHz
t_{SUGDDR}	Data Setup Before CLK	ECP3-70EA/95EA	321	—	403	—	535	—	ps
t_{HOGDDR}	Data Hold After CLK	ECP3-70EA/95EA	321	—	403	—	535	—	ps
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-70EA/95EA	—	405	—	325	—	250	MHz
t_{SUGDDR}	Data Setup Before CLK	ECP3-35EA	335	—	425	—	535	—	ps
t_{HOGDDR}	Data Hold After CLK	ECP3-35EA	335	—	425	—	535	—	ps
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-35EA	—	405	—	325	—	250	MHz
t_{SUGDDR}	Data Setup Before CLK	ECP3-17EA	335	—	425	—	535	—	ps
t_{HOGDDR}	Data Hold After CLK	ECP3-17EA	335	—	425	—	535	—	ps
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-17EA	—	405	—	325	—	250	MHz
Generic DDRX2 Inputs with Clock and Data (>10 Bits Wide) Aligned at Pin (GDDRX2_RX.ECLK.Aligned)									
Left and Right Side Using DLLCLKIN Pin for Clock Input									
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-150EA	—	0.225	—	0.225	—	0.225	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-150EA	0.775	—	0.775	—	0.775	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-150EA	—	460	—	385	—	345	MHz
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-70EA/95EA	—	0.225	—	0.225	—	0.225	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-70EA/95EA	0.775	—	0.775	—	0.775	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-70EA/95EA	—	460	—	385	—	311	MHz
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-35EA	—	0.210	—	0.210	—	0.210	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-35EA	0.790	—	0.790	—	0.790	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-35EA	—	460	—	385	—	311	MHz
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-17EA	—	0.210	—	0.210	—	0.210	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-17EA	0.790	—	0.790	—	0.790	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-17EA	—	460	—	385	—	311	MHz
Top Side Using PCLK Pin for Clock Input									
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-150EA	—	0.225	—	0.225	—	0.225	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-150EA	0.775	—	0.775	—	0.775	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-150EA	—	235	—	170	—	130	MHz
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-70EA/95EA	—	0.225	—	0.225	—	0.225	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-70EA/95EA	0.775	—	0.775	—	0.775	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-70EA/95EA	—	235	—	170	—	130	MHz
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-35EA	—	0.210	—	0.210	—	0.210	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-35EA	0.790	—	0.790	—	0.790	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-35EA	—	235	—	170	—	130	MHz
$t_{DVACLKGDDR}$	Data Setup Before CLK	ECP3-17EA	—	0.210	—	0.210	—	0.210	UI
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-17EA	0.790	—	0.790	—	0.790	—	UI
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-17EA	—	235	—	170	—	130	MHz

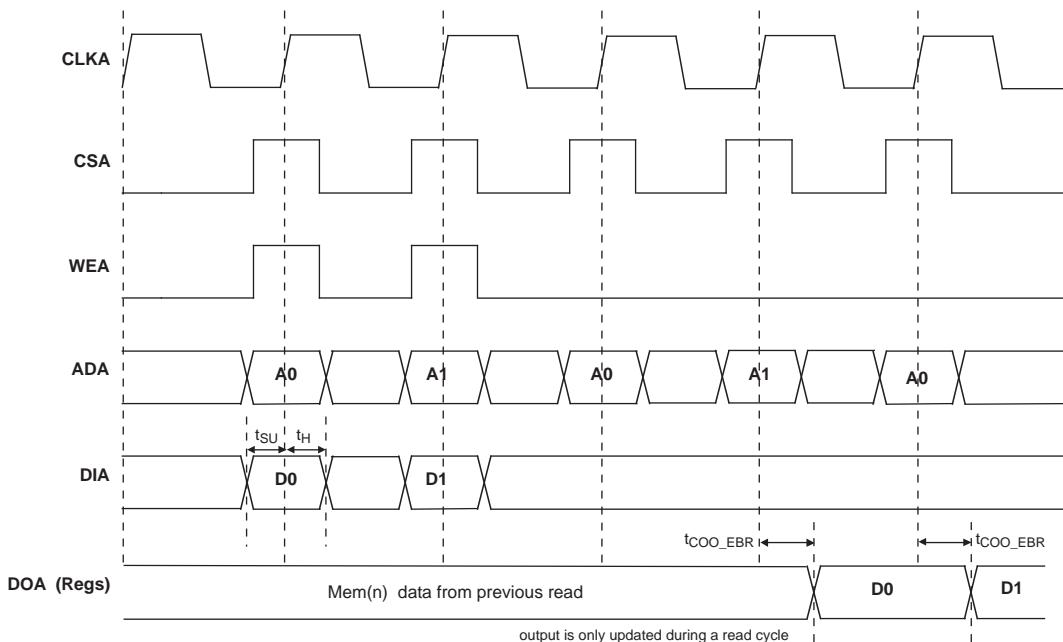
Timing Diagrams

Figure 3-9. Read/Write Mode (Normal)



Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.

Figure 3-10. Read/Write Mode with Input and Output Registers



LatticeECP3 Family Timing Adders^{1, 2, 3, 4, 5, 7}

Over Recommended Commercial Operating Conditions

Buffer Type	Description	-8	-7	-6	Units
Input Adjusters					
LVDS25E	LVDS, Emulated, VCCIO = 2.5 V	0.03	-0.01	-0.03	ns
LVDS25	LVDS, VCCIO = 2.5 V	0.03	0.00	-0.04	ns
BLVDS25	BLVDS, Emulated, VCCIO = 2.5 V	0.03	0.00	-0.04	ns
MLVDS25	MLVDS, Emulated, VCCIO = 2.5 V	0.03	0.00	-0.04	ns
RSDS25	RSDS, VCCIO = 2.5 V	0.03	-0.01	-0.03	ns
PPLVDS	Point-to-Point LVDS	0.03	-0.01	-0.03	ns
TRLVDS	Transition-Reduced LVDS	0.03	0.00	-0.04	ns
Mini MLVDS	Mini LVDS	0.03	-0.01	-0.03	ns
LVPECL33	LVPECL, Emulated, VCCIO = 3.3 V	0.17	0.23	0.28	ns
HSTL18_I	HSTL_18 class I, VCCIO = 1.8 V	0.20	0.17	0.13	ns
HSTL18_II	HSTL_18 class II, VCCIO = 1.8 V	0.20	0.17	0.13	ns
HSTL18D_I	Differential HSTL 18 class I	0.20	0.17	0.13	ns
HSTL18D_II	Differential HSTL 18 class II	0.20	0.17	0.13	ns
HSTL15_I	HSTL_15 class I, VCCIO = 1.5 V	0.10	0.12	0.13	ns
HSTL15D_I	Differential HSTL 15 class I	0.10	0.12	0.13	ns
SSTL33_I	SSTL_3 class I, VCCIO = 3.3 V	0.17	0.23	0.28	ns
SSTL33_II	SSTL_3 class II, VCCIO = 3.3 V	0.17	0.23	0.28	ns
SSTL33D_I	Differential SSTL_3 class I	0.17	0.23	0.28	ns
SSTL33D_II	Differential SSTL_3 class II	0.17	0.23	0.28	ns
SSTL25_I	SSTL_2 class I, VCCIO = 2.5 V	0.12	0.14	0.16	ns
SSTL25_II	SSTL_2 class II, VCCIO = 2.5 V	0.12	0.14	0.16	ns
SSTL25D_I	Differential SSTL_2 class I	0.12	0.14	0.16	ns
SSTL25D_II	Differential SSTL_2 class II	0.12	0.14	0.16	ns
SSTL18_I	SSTL_18 class I, VCCIO = 1.8 V	0.08	0.06	0.04	ns
SSTL18_II	SSTL_18 class II, VCCIO = 1.8 V	0.08	0.06	0.04	ns
SSTL18D_I	Differential SSTL_18 class I	0.08	0.06	0.04	ns
SSTL18D_II	Differential SSTL_18 class II	0.08	0.06	0.04	ns
SSTL15	SSTL_15, VCCIO = 1.5 V	0.087	0.059	0.032	ns
SSTL15D	Differential SSTL_15	0.087	0.059	0.032	ns
LVTTL33	LVTTL, VCCIO = 3.3 V	0.07	0.07	0.07	ns
LVCMOS33	LVCMOS, VCCIO = 3.3 V	0.07	0.07	0.07	ns
LVCMOS25	LVCMOS, VCCIO = 2.5 V	0.00	0.00	0.00	ns
LVCMOS18	LVCMOS, VCCIO = 1.8 V	-0.13	-0.13	-0.13	ns
LVCMOS15	LVCMOS, VCCIO = 1.5 V	-0.07	-0.07	-0.07	ns
LVCMOS12	LVCMOS, VCCIO = 1.2 V	-0.20	-0.19	-0.19	ns
PCI33	PCI, VCCIO = 3.3 V	0.07	0.07	0.07	ns
Output Adjusters					
LVDS25E	LVDS, Emulated, VCCIO = 2.5 V	1.02	1.14	1.26	ns
LVDS25	LVDS, VCCIO = 2.5 V	-0.11	-0.07	-0.03	ns
BLVDS25	BLVDS, Emulated, VCCIO = 2.5 V	1.01	1.13	1.25	ns
MLVDS25	MLVDS, Emulated, VCCIO = 2.5 V	1.01	1.13	1.25	ns

LatticeECP3 Family Timing Adders^{1, 2, 3, 4, 5, 7} (Continued)

Over Recommended Commercial Operating Conditions

Buffer Type	Description	-8	-7	-6	Units
RSDS25	RSDS, VCCIO = 2.5 V	-0.07	-0.04	-0.01	ns
PPLVDS	Point-to-Point LVDS, True LVDS, VCCIO = 2.5 V or 3.3 V	-0.22	-0.19	-0.16	ns
LVPECL33	LVPECL, Emulated, VCCIO = 3.3 V	0.67	0.76	0.86	ns
HSTL18_I	HSTL_18 class I 8mA drive, VCCIO = 1.8 V	1.20	1.34	1.47	ns
HSTL18_II	HSTL_18 class II, VCCIO = 1.8 V	0.89	1.00	1.11	ns
HSTL18D_I	Differential HSTL 18 class I 8 mA drive	1.20	1.34	1.47	ns
HSTL18D_II	Differential HSTL 18 class II	0.89	1.00	1.11	ns
HSTL15_I	HSTL_15 class I 4 mA drive, VCCIO = 1.5 V	1.67	1.83	1.99	ns
HSTL15D_I	Differential HSTL 15 class I 4 mA drive	1.67	1.83	1.99	ns
SSTL33_I	SSTL_3 class I, VCCIO = 3.3 V	1.12	1.17	1.21	ns
SSTL33_II	SSTL_3 class II, VCCIO = 3.3 V	1.08	1.12	1.15	ns
SSTL33D_I	Differential SSTL_3 class I	1.12	1.17	1.21	ns
SSTL33D_II	Differential SSTL_3 class II	1.08	1.12	1.15	ns
SSTL25_I	SSTL_2 class I 8 mA drive, VCCIO = 2.5 V	1.06	1.19	1.31	ns
SSTL25_II	SSTL_2 class II 16 mA drive, VCCIO = 2.5 V	1.04	1.17	1.31	ns
SSTL25D_I	Differential SSTL_2 class I 8 mA drive	1.06	1.19	1.31	ns
SSTL25D_II	Differential SSTL_2 class II 16 mA drive	1.04	1.17	1.31	ns
SSTL18_I	SSTL_1.8 class I, VCCIO = 1.8 V	0.70	0.84	0.97	ns
SSTL18_II	SSTL_1.8 class II 8 mA drive, VCCIO = 1.8 V	0.70	0.84	0.97	ns
SSTL18D_I	Differential SSTL_1.8 class I	0.70	0.84	0.97	ns
SSTL18D_II	Differential SSTL_1.8 class II 8 mA drive	0.70	0.84	0.97	ns
SSTL15	SSTL_1.5, VCCIO = 1.5 V	1.22	1.35	1.48	ns
SSTL15D	Differential SSTL_15	1.22	1.35	1.48	ns
LVTTL33_4mA	LVTTL 4 mA drive, VCCIO = 3.3V	0.25	0.24	0.23	ns
LVTTL33_8mA	LVTTL 8 mA drive, VCCIO = 3.3V	-0.06	-0.06	-0.07	ns
LVTTL33_12mA	LVTTL 12 mA drive, VCCIO = 3.3V	-0.01	-0.02	-0.02	ns
LVTTL33_16mA	LVTTL 16 mA drive, VCCIO = 3.3V	-0.07	-0.07	-0.08	ns
LVTTL33_20mA	LVTTL 20 mA drive, VCCIO = 3.3V	-0.12	-0.13	-0.14	ns
LVCMOS33_4mA	LVCMOS 3.3 4 mA drive, fast slew rate	0.25	0.24	0.23	ns
LVCMOS33_8mA	LVCMOS 3.3 8 mA drive, fast slew rate	-0.06	-0.06	-0.07	ns
LVCMOS33_12mA	LVCMOS 3.3 12 mA drive, fast slew rate	-0.01	-0.02	-0.02	ns
LVCMOS33_16mA	LVCMOS 3.3 16 mA drive, fast slew rate	-0.07	-0.07	-0.08	ns
LVCMOS33_20mA	LVCMOS 3.3 20 mA drive, fast slew rate	-0.12	-0.13	-0.14	ns
LVCMOS25_4mA	LVCMOS 2.5 4 mA drive, fast slew rate	0.12	0.10	0.09	ns
LVCMOS25_8mA	LVCMOS 2.5 8 mA drive, fast slew rate	-0.05	-0.06	-0.07	ns
LVCMOS25_12mA	LVCMOS 2.5 12 mA drive, fast slew rate	0.00	0.00	0.00	ns
LVCMOS25_16mA	LVCMOS 2.5 16 mA drive, fast slew rate	-0.12	-0.13	-0.14	ns
LVCMOS25_20mA	LVCMOS 2.5 20 mA drive, fast slew rate	-0.12	-0.13	-0.14	ns
LVCMOS18_4mA	LVCMOS 1.8 4 mA drive, fast slew rate	0.11	0.12	0.14	ns
LVCMOS18_8mA	LVCMOS 1.8 8 mA drive, fast slew rate	0.11	0.12	0.14	ns
LVCMOS18_12mA	LVCMOS 1.8 12 mA drive, fast slew rate	-0.04	-0.03	-0.03	ns
LVCMOS18_16mA	LVCMOS 1.8 16 mA drive, fast slew rate	-0.04	-0.03	-0.03	ns

LatticeECP3 Family Timing Adders^{1, 2, 3, 4, 5, 7} (Continued)

Over Recommended Commercial Operating Conditions

Buffer Type	Description	-8	-7	-6	Units
LVCMOS15_4mA	LVCMOS 1.5 4 mA drive, fast slew rate	0.21	0.25	0.29	ns
LVCMOS15_8mA	LVCMOS 1.5 8 mA drive, fast slew rate	0.05	0.07	0.09	ns
LVCMOS12_2mA	LVCMOS 1.2 2 mA drive, fast slew rate	0.43	0.51	0.59	ns
LVCMOS12_6mA	LVCMOS 1.2 6 mA drive, fast slew rate	0.23	0.28	0.33	ns
LVCMOS33_4mA	LVCMOS 3.3 4 mA drive, slow slew rate	1.44	1.58	1.72	ns
LVCMOS33_8mA	LVCMOS 3.3 8 mA drive, slow slew rate	0.98	1.10	1.22	ns
LVCMOS33_12mA	LVCMOS 3.3 12 mA drive, slow slew rate	0.67	0.77	0.86	ns
LVCMOS33_16mA	LVCMOS 3.3 16 mA drive, slow slew rate	0.97	1.09	1.21	ns
LVCMOS33_20mA	LVCMOS 3.3 20 mA drive, slow slew rate	0.67	0.76	0.85	ns
LVCMOS25_4mA	LVCMOS 2.5 4 mA drive, slow slew rate	1.48	1.63	1.78	ns
LVCMOS25_8mA	LVCMOS 2.5 8 mA drive, slow slew rate	1.02	1.14	1.27	ns
LVCMOS25_12mA	LVCMOS 2.5 12 mA drive, slow slew rate	0.74	0.84	0.94	ns
LVCMOS25_16mA	LVCMOS 2.5 16 mA drive, slow slew rate	1.02	1.14	1.26	ns
LVCMOS25_20mA	LVCMOS 2.5 20 mA drive, slow slew rate	0.74	0.83	0.93	ns
LVCMOS18_4mA	LVCMOS 1.8 4 mA drive, slow slew rate	1.60	1.77	1.93	ns
LVCMOS18_8mA	LVCMOS 1.8 8 mA drive, slow slew rate	1.11	1.25	1.38	ns
LVCMOS18_12mA	LVCMOS 1.8 12 mA drive, slow slew rate	0.87	0.98	1.09	ns
LVCMOS18_16mA	LVCMOS 1.8 16 mA drive, slow slew rate	0.86	0.97	1.07	ns
LVCMOS15_4mA	LVCMOS 1.5 4 mA drive, slow slew rate	1.71	1.89	2.08	ns
LVCMOS15_8mA	LVCMOS 1.5 8 mA drive, slow slew rate	1.20	1.34	1.48	ns
LVCMOS12_2mA	LVCMOS 1.2 2 mA drive, slow slew rate	1.37	1.56	1.74	ns
LVCMOS12_6mA	LVCMOS 1.2 6 mA drive, slow slew rate	1.11	1.27	1.43	ns
PCI33	PCI, VCCIO = 3.3 V	-0.12	-0.13	-0.14	ns

1. Timing adders are characterized but not tested on every device.
2. LVCMOS timing measured with the load specified in Switching Test Condition table.
3. All other standards tested according to the appropriate specifications.
4. Not all I/O standards and drive strengths are supported for all banks. See the Architecture section of this data sheet for details.
5. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from the Diamond or ispLEVER software.
6. This data does not apply to the LatticeECP3-17EA device.
7. For details on -9 speed grade devices, please contact your Lattice Sales Representative.

Serial Rapid I/O Type 2/CPRI LV E.24 Electrical and Timing Characteristics

AC and DC Characteristics

Table 3-15. Transmit

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
T _{RF} ¹	Differential rise/fall time	20%-80%	—	80	—	ps
Z _{TX_DIFF_DC}	Differential impedance		80	100	120	Ohms
J _{TX_DDJ} ^{3, 4, 5}	Output data deterministic jitter		—	—	0.17	UI
J _{TX_TJ} ^{2, 3, 4, 5}	Total output data jitter		—	—	0.35	UI

1. Rise and Fall times measured with board trace, connector and approximately 2.5pf load.
2. Total jitter includes both deterministic jitter and random jitter. The random jitter is the total jitter minus the actual deterministic jitter.
3. Jitter values are measured with each CML output AC coupled into a 50-Ohm impedance (100-Ohm differential impedance).
4. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
5. Values are measured at 2.5 Gbps.

Table 3-16. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
RL _{RX_DIFF}	Differential return loss	From 100 MHz to 2.5 GHz	10	—	—	dB
RL _{RX_CM}	Common mode return loss	From 100 MHz to 2.5 GHz	6	—	—	dB
Z _{RX_DIFF}	Differential termination resistance		80	100	120	Ohms
J _{RX_DJ} ^{2, 3, 4, 5}	Deterministic jitter tolerance (peak-to-peak)		—	—	0.37	UI
J _{RX_RJ} ^{2, 3, 4, 5}	Random jitter tolerance (peak-to-peak)		—	—	0.18	UI
J _{RX_SJ} ^{2, 3, 4, 5}	Sinusoidal jitter tolerance (peak-to-peak)		—	—	0.10	UI
J _{RX_TJ} ^{1, 2, 3, 4, 5}	Total jitter tolerance (peak-to-peak)		—	—	0.65	UI
T _{RX_EYE}	Receiver eye opening		0.35	—	—	UI

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter. The sinusoidal jitter tolerance mask is shown in Figure 3-18.
2. Jitter values are measured with each high-speed input AC coupled into a 50-Ohm impedance.
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.
5. Values are measured at 2.5 Gbps.

SMPTE SD/HD-SDI/3G-SDI (Serial Digital Interface) Electrical and Timing Characteristics

AC and DC Characteristics

Table 3-19. Transmit

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
BR _{SDO}	Serial data rate		270	—	2975	Mbps
T _{JALIGNMENT} ²	Serial output jitter, alignment	270 Mbps	—	—	0.20	UI
T _{JALIGNMENT} ²	Serial output jitter, alignment	1485 Mbps	—	—	0.20	UI
T _{JALIGNMENT} ^{1,2}	Serial output jitter, alignment	2970Mbps	—	—	0.30	UI
T _{JTIMING}	Serial output jitter, timing	270 Mbps	—	—	0.20	UI
T _{JTIMING}	Serial output jitter, timing	1485 Mbps	—	—	1.0	UI
T _{JTIMING}	Serial output jitter, timing	2970 Mbps	—	—	2.0	UI

Notes:

1. Timing jitter is measured in accordance with SMPTE RP 184-1996, SMPTE RP 192-1996 and the applicable serial data transmission standard, SMPTE 259M-1997 or SMPTE 292M (proposed). A color bar test pattern is used. The value of f_{SCLK} is 270 MHz or 360 MHz for SMPTE 259M, 540 MHz for SMPTE 344M or 1485 MHz for SMPTE 292M serial data rates. See the Timing Jitter Bandpass section.
2. Jitter is defined in accordance with SMPTE RP1 184-1996 as: jitter at an equipment output in the absence of input jitter.
3. All Tx jitter is measured at the output of an industry standard cable driver; connection to the cable driver is via a 50 Ohm impedance differential signal from the Lattice SERDES device.
4. The cable driver drives: RL=75 Ohm, AC-coupled at 270, 1485, or 2970 Mbps, RREFLVL=RREFPRE=4.75 kOhm 1%.

Table 3-20. Receive

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
BR _{SDI}	Serial input data rate		270	—	2970	Mbps
CID	Stream of non-transitions (=Consecutive Identical Digits)		7(3G)/26(SMPTE Triple rates) @ 10-12 BER	—	—	Bits

Table 3-21. Reference Clock

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
F _{VCLK}	Video output clock frequency		27	—	74.25	MHz
DC _V	Duty cycle, video clock		45	50	55	%

Figure 3-28. Master SPI Configuration Waveforms

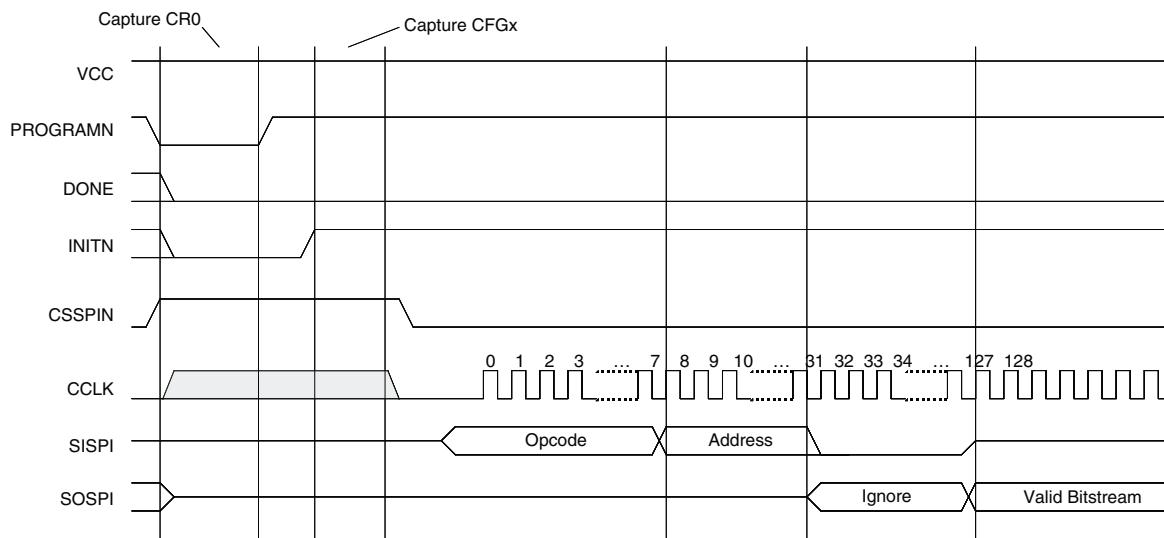
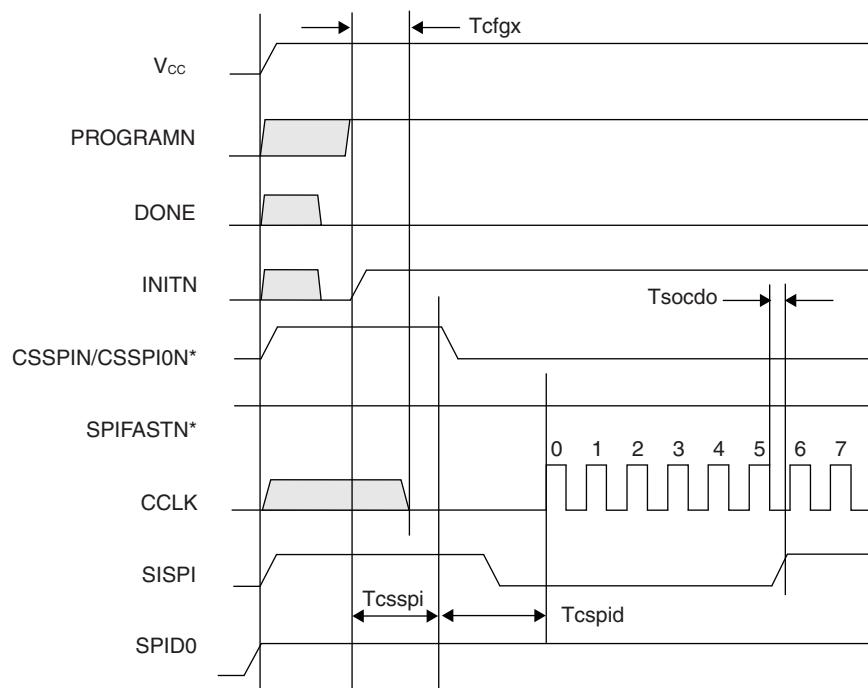


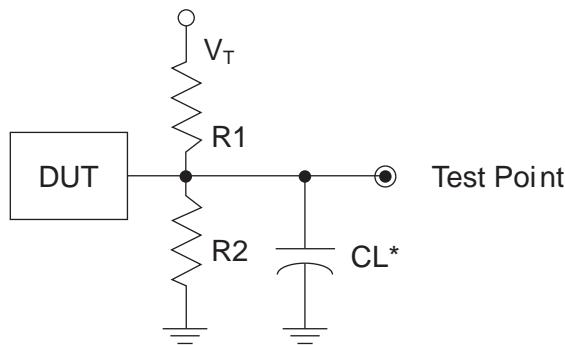
Figure 3-29. Master SPI POR Waveforms



Switching Test Conditions

Figure 3-33 shows the output test load that is used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-23.

Figure 3-33. Output Test Load, LVTTL and LVC MOS Standards



*CL Includes Test Fixture and Probe Capacitance

Table 3-23. Test Fixture Required Components, Non-Terminated Interfaces

Test Condition	R ₁	R ₂	C _L	Timing Ref.	V _T
LVTTL and other LVC MOS settings (L → H, H → L)	∞	∞	0 pF	LVC MOS 3.3 = V _{CCIO} /2	—
				LVC MOS 2.5 = V _{CCIO} /2	—
				LVC MOS 1.8 = V _{CCIO} /2	—
				LVC MOS 1.5 = V _{CCIO} /2	—
				LVC MOS 1.2 = V _{CCIO} /2	—
LVC MOS 2.5 I/O (Z → H)	∞	1 MΩ	0 pF	V _{CCIO} /2	—
LVC MOS 2.5 I/O (Z → L)	1 MΩ	∞	0 pF	V _{CCIO} /2	V _{CCIO}
LVC MOS 2.5 I/O (H → Z)	∞	100	0 pF	V _{OH} - 0.10	—
LVC MOS 2.5 I/O (L → Z)	100	∞	0 pF	V _{OL} + 0.10	V _{CCIO}

Note: Output test conditions for all other interfaces are determined by the respective standards.

Pin Information Summary (Cont.)

Pin Information Summary		ECP3-95EA			ECP3-150EA	
Pin Type		484 fpBGA	672 fpBGA	1156 fpBGA	672 fpBGA	1156 fpBGA
Emulated Differential I/O per Bank	Bank 0	21	30	43	30	47
	Bank 1	18	24	39	24	43
	Bank 2	8	12	13	12	18
	Bank 3	20	23	33	23	37
	Bank 6	22	25	33	25	37
	Bank 7	11	16	18	16	24
	Bank 8	12	12	12	12	12
Highspeed Differential I/O per Bank	Bank 0	0	0	0	0	0
	Bank 1	0	0	0	0	0
	Bank 2	6	9	9	9	15
	Bank 3	9	12	16	12	21
	Bank 6	11	14	16	14	21
	Bank 7	9	12	13	12	18
	Bank 8	0	0	0	0	0
Total Single Ended/ Total Differential I/O per Bank	Bank 0	42/21	60/30	86/43	60/30	94/47
	Bank 1	36/18	48/24	78/39	48/24	86/43
	Bank 2	28/14	42/21	44/22	42/21	66/33
	Bank 3	58/29	71/35	98/49	71/35	116/58
	Bank 6	67/33	78/39	98/49	78/39	116/58
	Bank 7	40/20	56/28	62/31	56/28	84/42
	Bank 8	24/12	24/12	24/12	24/12	24/12
DDR Groups Bonded per Bank	Bank 0	3	5	7	5	7
	Bank 1	3	4	7	4	7
	Bank 2	2	3	3	3	4
	Bank 3	3	4	5	4	7
	Bank 6	4	4	5	4	7
	Bank 7	3	4	4	4	6
	Configuration Bank8	0	0	0	0	0
SERDES Quads		1	2	3	2	4

1. These pins must remain floating on the board.

Industrial

The following devices may have associated errata. Specific devices with associated errata will be notated with a footnote.

Part Number	Voltage	Grade	Power	Package ¹	Pins	Temp.	LUTs (K)
LFE3-17EA-6FTN256I	1.2 V	-6	STD	Lead-Free ftBGA	256	IND	17
LFE3-17EA-7FTN256I	1.2 V	-7	STD	Lead-Free ftBGA	256	IND	17
LFE3-17EA-8FTN256I	1.2 V	-8	STD	Lead-Free ftBGA	256	IND	17
LFE3-17EA-6LFTN256I	1.2 V	-6	LOW	Lead-Free ftBGA	256	IND	17
LFE3-17EA-7LFTN256I	1.2 V	-7	LOW	Lead-Free ftBGA	256	IND	17
LFE3-17EA-8LFTN256I	1.2 V	-8	LOW	Lead-Free ftBGA	256	IND	17
LFE3-17EA-6MG328I	1.2 V	-6	STD	Lead-Free csBGA	328	IND	17
LFE3-17EA-7MG328I	1.2 V	-7	STD	Lead-Free csBGA	328	IND	17
LFE3-17EA-8MG328I	1.2 V	-8	STD	Lead-Free csBGA	328	IND	17
LFE3-17EA-6LMG328I	1.2 V	-6	LOW	Green csBGA	328	IND	17
LFE3-17EA-7LMG328I	1.2 V	-7	LOW	Green csBGA	328	IND	17
LFE3-17EA-8LMG328I	1.2 V	-8	LOW	Green csBGA	328	IND	17
LFE3-17EA-6FN484I	1.2 V	-6	STD	Lead-Free fpBGA	484	IND	17
LFE3-17EA-7FN484I	1.2 V	-7	STD	Lead-Free fpBGA	484	IND	17
LFE3-17EA-8FN484I	1.2 V	-8	STD	Lead-Free fpBGA	484	IND	17
LFE3-17EA-6LFN484I	1.2 V	-6	LOW	Lead-Free fpBGA	484	IND	17
LFE3-17EA-7LFN484I	1.2 V	-7	LOW	Lead-Free fpBGA	484	IND	17
LFE3-17EA-8LFN484I	1.2 V	-8	LOW	Lead-Free fpBGA	484	IND	17

1. Green = Halogen free and lead free.

Part Number	Voltage	Grade ¹	Power	Package	Pins	Temp.	LUTs (K)
LFE3-35EA-6FTN256I	1.2 V	-6	STD	Lead-Free ftBGA	256	IND	33
LFE3-35EA-7FTN256I	1.2 V	-7	STD	Lead-Free ftBGA	256	IND	33
LFE3-35EA-8FTN256I	1.2 V	-8	STD	Lead-Free ftBGA	256	IND	33
LFE3-35EA-6LFTN256I	1.2 V	-6	LOW	Lead-Free ftBGA	256	IND	33
LFE3-35EA-7LFTN256I	1.2 V	-7	LOW	Lead-Free ftBGA	256	IND	33
LFE3-35EA-8LFTN256I	1.2 V	-8	LOW	Lead-Free ftBGA	256	IND	33
LFE3-35EA-6FN484I	1.2 V	-6	STD	Lead-Free fpBGA	484	IND	33
LFE3-35EA-7FN484I	1.2 V	-7	STD	Lead-Free fpBGA	484	IND	33
LFE3-35EA-8FN484I	1.2 V	-8	STD	Lead-Free fpBGA	484	IND	33
LFE3-35EA-6LFN484I	1.2 V	-6	LOW	Lead-Free fpBGA	484	IND	33
LFE3-35EA-7LFN484I	1.2 V	-7	LOW	Lead-Free fpBGA	484	IND	33
LFE3-35EA-8LFN484I	1.2 V	-8	LOW	Lead-Free fpBGA	484	IND	33
LFE3-35EA-6FN672I	1.2 V	-6	STD	Lead-Free fpBGA	672	IND	33
LFE3-35EA-7FN672I	1.2 V	-7	STD	Lead-Free fpBGA	672	IND	33
LFE3-35EA-8FN672I	1.2 V	-8	STD	Lead-Free fpBGA	672	IND	33
LFE3-35EA-6LFN672I	1.2 V	-6	LOW	Lead-Free fpBGA	672	IND	33
LFE3-35EA-7LFN672I	1.2 V	-7	LOW	Lead-Free fpBGA	672	IND	33
LFE3-35EA-8LFN672I	1.2 V	-8	LOW	Lead-Free fpBGA	672	IND	33

1. For ordering information on -9 speed grade devices, please contact your Lattice Sales Representative.



Ordering Information
LatticeECP3 Family Data Sheet

Part Number	Voltage	Grade ¹	Power	Package	Pins	Temp.	LUTs (K)
LFE3-70EA-6FN484I	1.2 V	-6	STD	Lead-Free fpBGA	484	IND	67
LFE3-70EA-7FN484I	1.2 V	-7	STD	Lead-Free fpBGA	484	IND	67
LFE3-70EA-8FN484I	1.2 V	-8	STD	Lead-Free fpBGA	484	IND	67
LFE3-70EA-6LFN484I	1.2 V	-6	LOW	Lead-Free fpBGA	484	IND	67
LFE3-70EA-7LFN484I	1.2 V	-7	LOW	Lead-Free fpBGA	484	IND	67
LFE3-70EA-8LFN484I	1.2 V	-8	LOW	Lead-Free fpBGA	484	IND	67
LFE3-70EA-6FN672I	1.2 V	-6	STD	Lead-Free fpBGA	672	IND	67
LFE3-70EA-7FN672I	1.2 V	-7	STD	Lead-Free fpBGA	672	IND	67
LFE3-70EA-8FN672I	1.2 V	-8	STD	Lead-Free fpBGA	672	IND	67
LFE3-70EA-6LFN672I	1.2 V	-6	LOW	Lead-Free fpBGA	672	IND	67
LFE3-70EA-7LFN672I	1.2 V	-7	LOW	Lead-Free fpBGA	672	IND	67
LFE3-70EA-8LFN672I	1.2 V	-8	LOW	Lead-Free fpBGA	672	IND	67
LFE3-70EA-6FN1156I	1.2 V	-6	STD	Lead-Free fpBGA	1156	IND	67
LFE3-70EA-7FN1156I	1.2 V	-7	STD	Lead-Free fpBGA	1156	IND	67
LFE3-70EA-8FN1156I	1.2 V	-8	STD	Lead-Free fpBGA	1156	IND	67
LFE3-70EA-6LFN1156I	1.2 V	-6	LOW	Lead-Free fpBGA	1156	IND	67
LFE3-70EA-7LFN1156I	1.2 V	-7	LOW	Lead-Free fpBGA	1156	IND	67
LFE3-70EA-8LFN1156I	1.2 V	-8	LOW	Lead-Free fpBGA	1156	IND	67

1. For ordering information on -9 speed grade devices, please contact your Lattice Sales Representative.

Part Number	Voltage	Grade ¹	Power	Package	Pins	Temp.	LUTs (K)
LFE3-95EA-6FN484I	1.2 V	-6	STD	Lead-Free fpBGA	484	IND	92
LFE3-95EA-7FN484I	1.2 V	-7	STD	Lead-Free fpBGA	484	IND	92
LFE3-95EA-8FN484I	1.2 V	-8	STD	Lead-Free fpBGA	484	IND	92
LFE3-95EA-6LFN484I	1.2 V	-6	LOW	Lead-Free fpBGA	484	IND	92
LFE3-95EA-7LFN484I	1.2 V	-7	LOW	Lead-Free fpBGA	484	IND	92
LFE3-95EA-8LFN484I	1.2 V	-8	LOW	Lead-Free fpBGA	484	IND	92
LFE3-95EA-6FN672I	1.2 V	-6	STD	Lead-Free fpBGA	672	IND	92
LFE3-95EA-7FN672I	1.2 V	-7	STD	Lead-Free fpBGA	672	IND	92
LFE3-95EA-8FN672I	1.2 V	-8	STD	Lead-Free fpBGA	672	IND	92
LFE3-95EA-6LFN672I	1.2 V	-6	LOW	Lead-Free fpBGA	672	IND	92
LFE3-95EA-7LFN672I	1.2 V	-7	LOW	Lead-Free fpBGA	672	IND	92
LFE3-95EA-8LFN672I	1.2 V	-8	LOW	Lead-Free fpBGA	672	IND	92
LFE3-95EA-6FN1156I	1.2 V	-6	STD	Lead-Free fpBGA	1156	IND	92
LFE3-95EA-7FN1156I	1.2 V	-7	STD	Lead-Free fpBGA	1156	IND	92
LFE3-95EA-8FN1156I	1.2 V	-8	STD	Lead-Free fpBGA	1156	IND	92
LFE3-95EA-6LFN1156I	1.2 V	-6	LOW	Lead-Free fpBGA	1156	IND	92
LFE3-95EA-7LFN1156I	1.2 V	-7	LOW	Lead-Free fpBGA	1156	IND	92
LFE3-95EA-8LFN1156I	1.2 V	-8	LOW	Lead-Free fpBGA	1156	IND	92

1. For ordering information on -9 speed grade devices, please contact your Lattice Sales Representative.

Date	Version	Section	Change Summary
			Updated Simplified Channel Block Diagram for SERDES/PCS Block diagram. Updated Device Configuration text section. Corrected software default value of MCCLK to be 2.5 MHz.
		DC and Switching Characteristics	Updated VCCOB Min/Max data in Recommended Operating Conditions table. Corrected footnote 2 in sysIO Recommended Operating Conditions table. Added added footnote 7 for t_{SKEW_PRIB} to External Switching Characteristics table. Added 2-to-1 Gearing text section and table. Updated External Reference Clock Specification (refclkp/refclkn) table. LatticeECP3 sysCONFIG Port Timing Specifications - updated t_{DINIT} information. Added sysCONFIG Port Timing waveform. Serial Input Data Specifications table, delete Typ data for $V_{RX\text{-}DIFF\text{-}S}$. Added footnote 4 to sysCLOCK PLL Timing table for t_{PFD} . Added SERDES/PCS Block Latency Breakdown table. External Reference Clock Specifications table, added footnote 4, add symbol name vREF-IN-DIFF. Added SERDES External Reference Clock Waveforms. Updated Serial Output Timing and Levels table. Pin-to-pin performance table, changed "typically 3% slower" to "typically slower". Updated timing information Updated SERDES minimum frequency.
			Added data to the following tables: External Switching Characteristics, Internal Switching Characteristics, Family Timing Adders, Maximum I/O Buffer Speed, DLL Timing, High Speed Data Transmitter, Channel Output Jitter, Typical Building Block Function Performance, Register-to-Register Performance, and Power Supply Requirements. Updated Serial Input Data Specifications table. Updated Transmit table, Serial Rapid I/O Type 2 Electrical and Timing Characteristics section.
		Pinout Information	Updated Signal Description tables. Updated Pin Information Summary tables and added footnote 1.
February 2009	01.0	—	Initial release.